



Product/Process Change Notice - PCN 20_0018 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: ADL5205 Die Revision

Publication Date: 17-Jan-2020

Effectivity Date: 20-Apr-2020 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release.

Description Of Change:

Remove two FETs from bias line on main current source of the DAC with a metal 2 cut.

Reason For Change:

This change is to fix single channel mode low temp low supply gain setting error.

Impact of the change (positive or negative) on fit, form, function & reliability:

This change addresses the issue with single channel mode low temp low supply gain setting error. Has no impact on the fit, form function and reliability. Product specification is not affected by this change.

Product Identification *(this section will describe how to identify the changed material)*

Product date code of new material to be advised on a later revision of this PCN.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

ADI_PCN_20_0018_Rev_-_ADL5205_Qualification Results Summary.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:
PCN_Americas@analog.com

Europe:
PCN_Europe@analog.com

Japan:
PCN_Japan@analog.com

Rest of Asia:
PCN_ROA@analog.com

Appendix A - Affected ADI Models

Added Parts On This Revision - Product Family / Model Number (1)

ADL5205 / ADL5205ACPZ-R7				
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Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	17-Jan-2020	20-Apr-2020	Initial Release.

Analog Devices, Inc.

DocId:7967 Parent DocId:4589 Layout Rev:7

Qualification Results Summary of ADL5205

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Solder Heat Resistance (SHR)*	JEDEC <i>J-STD-020</i>	1*30	Pass
Latch-Up	JEDEC <i>JESD78</i>	1*3	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass 3kV
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JS-002</i>	3/voltage	Pass 250V

*Preconditioned per JEDEC/IPC J-STD-020